

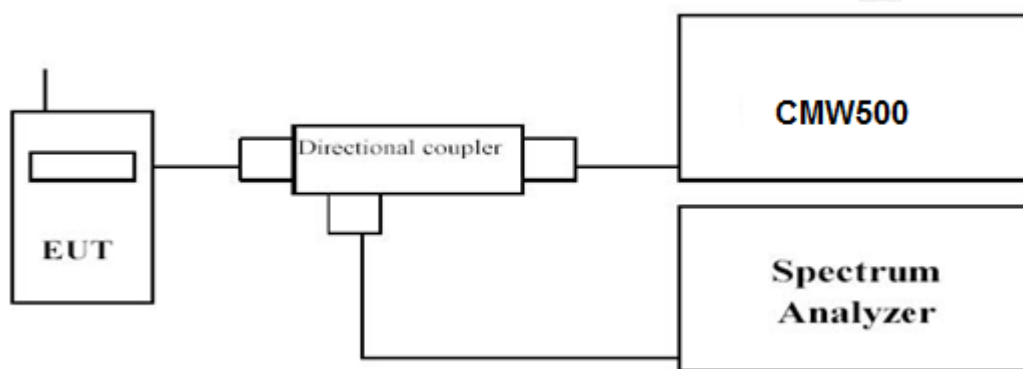
3.5 Spurious Emission

LIMIT

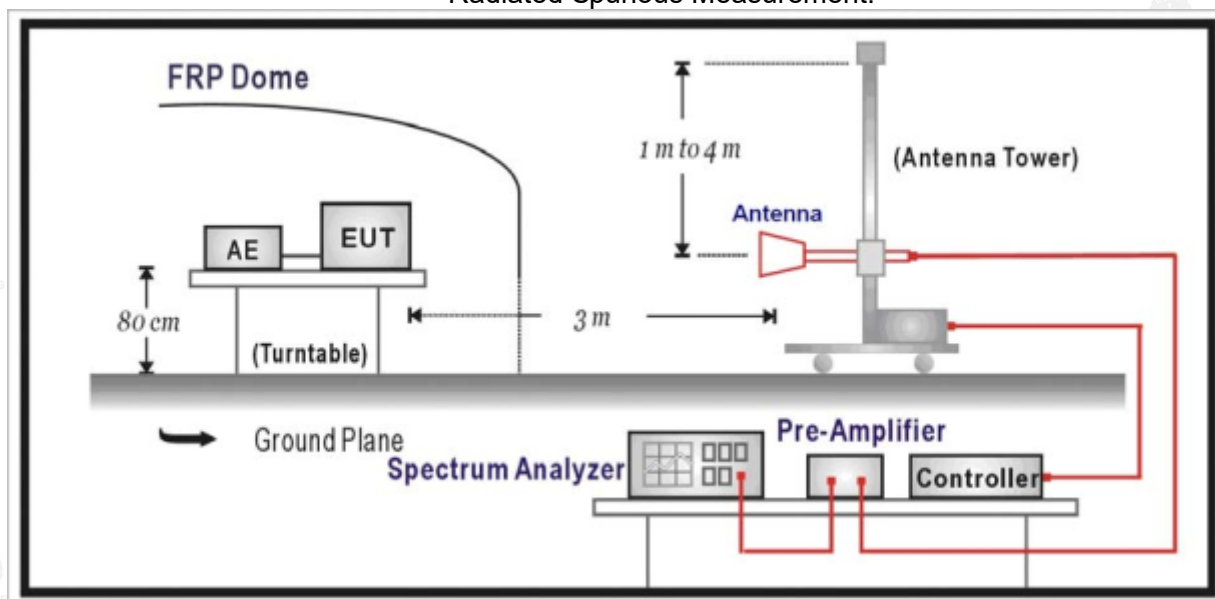
According to §27.53 (h): For operations in the 1710–1755 MHz and 2110–2155 MHz bands, the power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) by at least $43 + 10 \log_{10}(P)$ dB.

TEST CONFIGURATION

Conducted Spurious Measurement:



Radiated Spurious Measurement:



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D.

Conducted Spurious Measurement:

- Place the EUT on a bench and set it in transmitting mode.
- Connect a low loss RF cable from the antenna port to a spectrum analyzer and CMW500 by a Directional Couple.
- EUT Communicate with CMW500, then select a channel for testing.
- Add a correction factor to the display of spectrum, and then test.
- The resolution bandwidth of the spectrum analyzer was set sufficient scans were taken to show the out of band Emission if any up to 10^{th} harmonic.

f. Please refer to following tables for test antenna conducted emissions.

Working Frequency	Sub range (GHz)	RBW	VBW	Sweep time (s)
LTE FDD Band 66	0.03~1	100KHz	300KHz	Auto
	1~3	1 MHz	3 MHz	Auto
	3~20	1 MHz	3 MHz	Auto

Radiated Spurious Measurement:

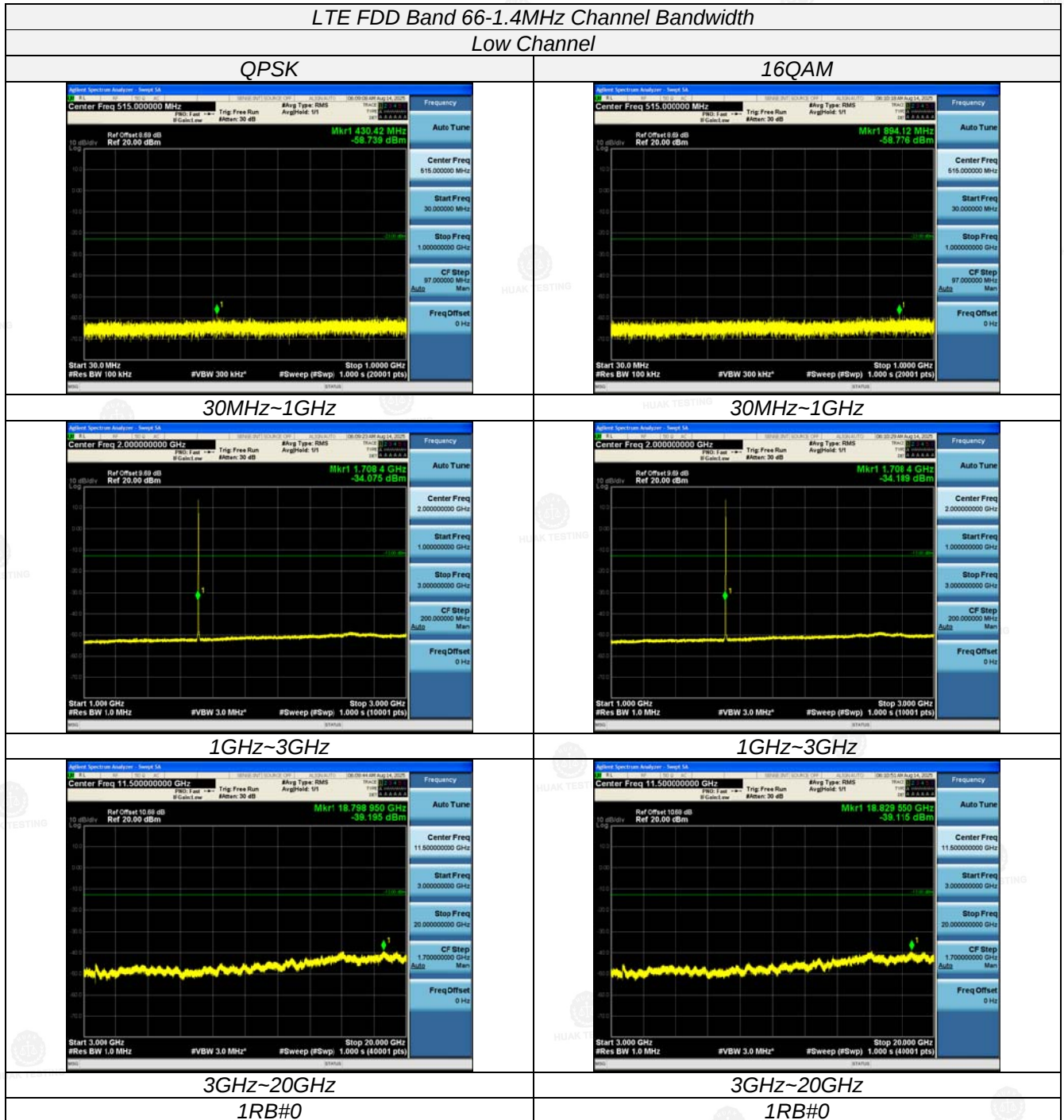
- The EUT shall be placed at the specified height on a support, and in the position closest to normal use as declared by provider.
- The test antenna shall be oriented initially for vertical polarization and shall be chosen to correspond to the frequency of the transmitter.
- The output of the test antenna shall be connected to the measuring receiver.
- The transmitter shall be switched on and the measuring receiver shall be tuned to the frequency of the transmitter under test.
- The test antenna shall be raised and lowered through the specified range of height until a maximum signal level is detected by the measuring receiver.
- The transmitter shall then be rotated through 360° in the horizontal plane, until the maximum signal level is detected by the measuring receiver.
- The test antenna shall be raised and lowered again through the specified range of height until a maximum signal level is detected by the measuring receiver.
- The maximum signal level detected by the measuring receiver shall be noted.
- The transmitter shall be replaced by a substitution antenna.
- The substitution antenna shall be orientated for vertical polarization and the length of the substitution antenna shall be adjusted to correspond to the frequency of the transmitter.
- The substitution antenna shall be connected to a calibrated signal generator.
- If necessary, the input attenuator setting of the measuring receiver shall be adjusted in order to increase the sensitivity of the measuring receiver.
- The test antenna shall be raised and lowered through the specified range of height to ensure that the maximum signal is received.
- The input signal to the substitution antenna shall be adjusted to the level that produces a level detected by the measuring receiver, that is equal to the level noted while the transmitter radiated power was measured, corrected for the change of input attenuator setting of the measuring receiver.
- The measurement shall be repeated with the test antenna and the substitution antenna orientated for horizontal polarization.
- The measure of the effective radiated power is the larger of the two levels recorded at the input to the substitution antenna, corrected for gain of the substitution antenna if necessary.
- The resolution bandwidth of the spectrum analyzer was set at 100 kHz for Part 22 and 1MHz for Part 24. The frequency range was checked up to 10th harmonic.
- Test site anechoic chamber refer to ANSI C63.

TEST RESULTS

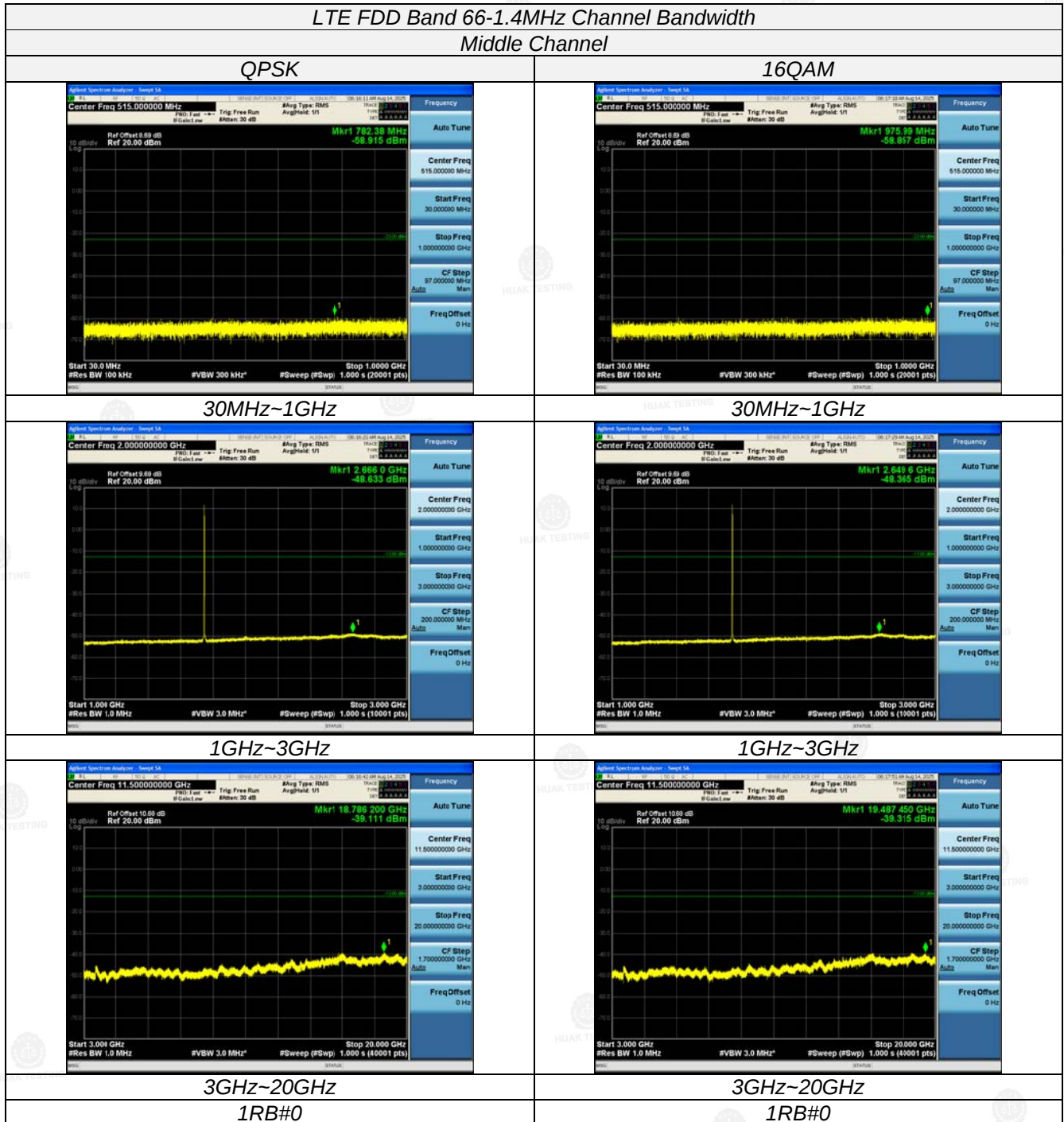
Remark:

- We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 66; recorded worst case for each Channel Bandwidth of LTE FDD Band 66.*

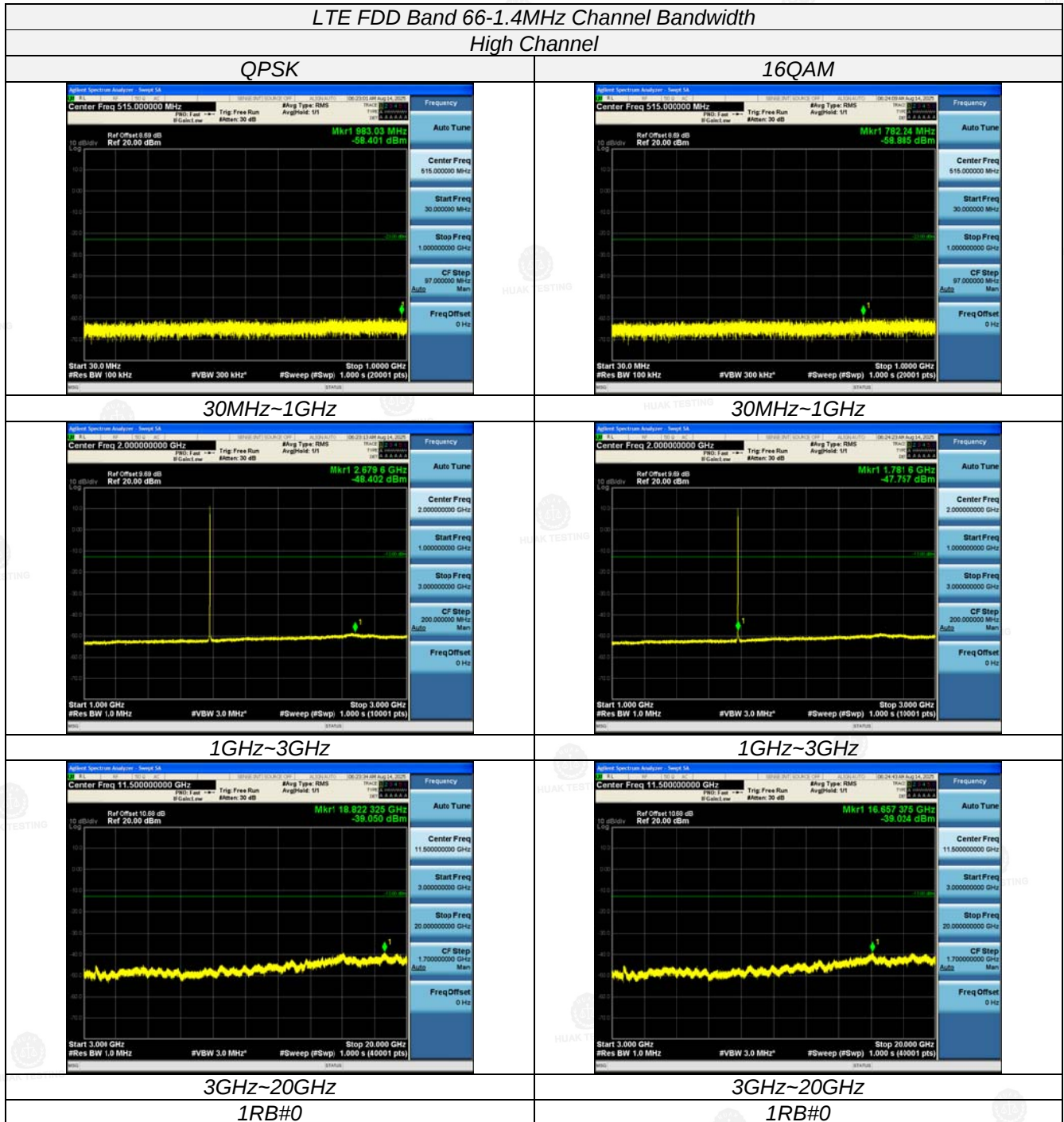
Conducted Measurement:



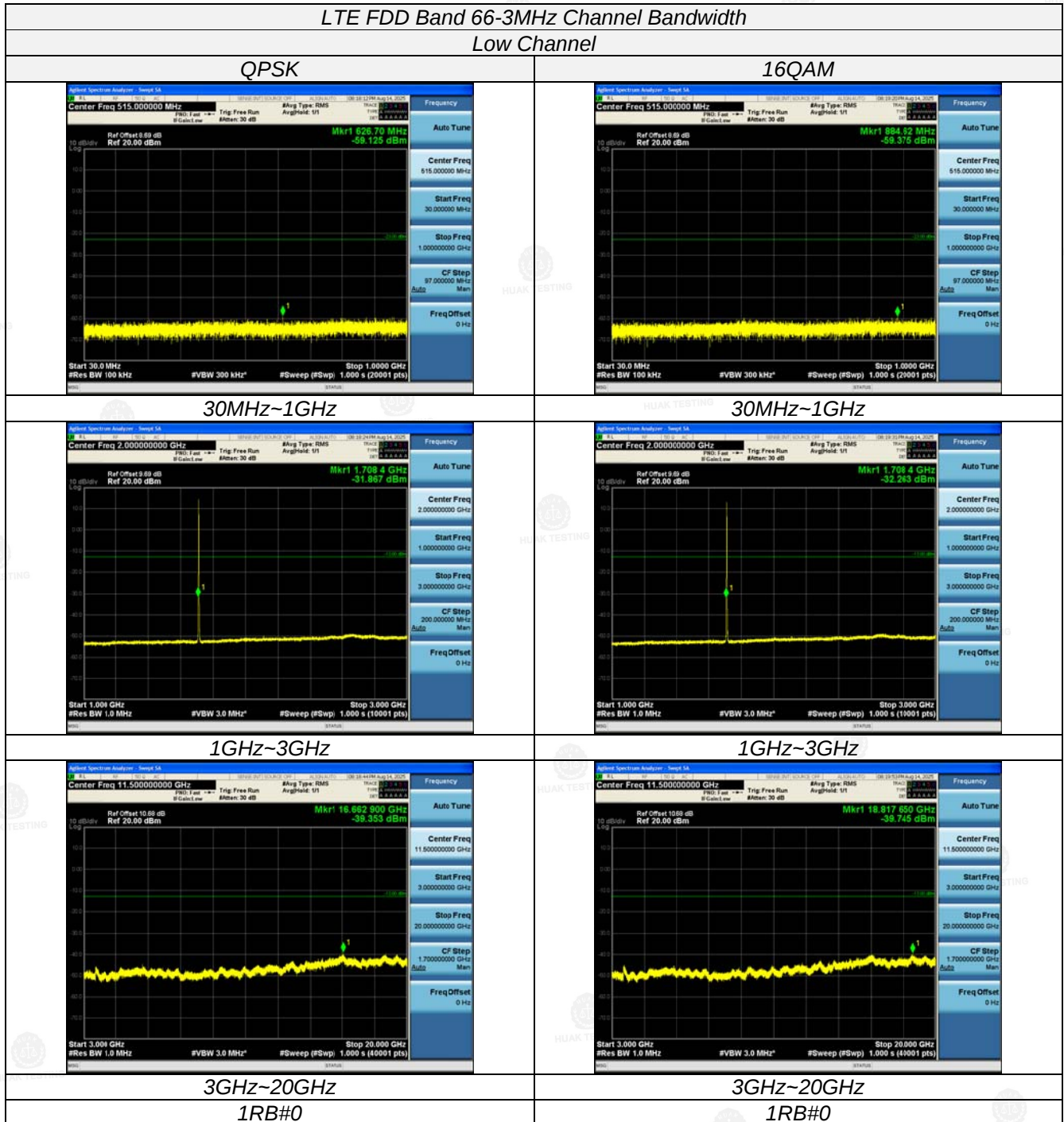
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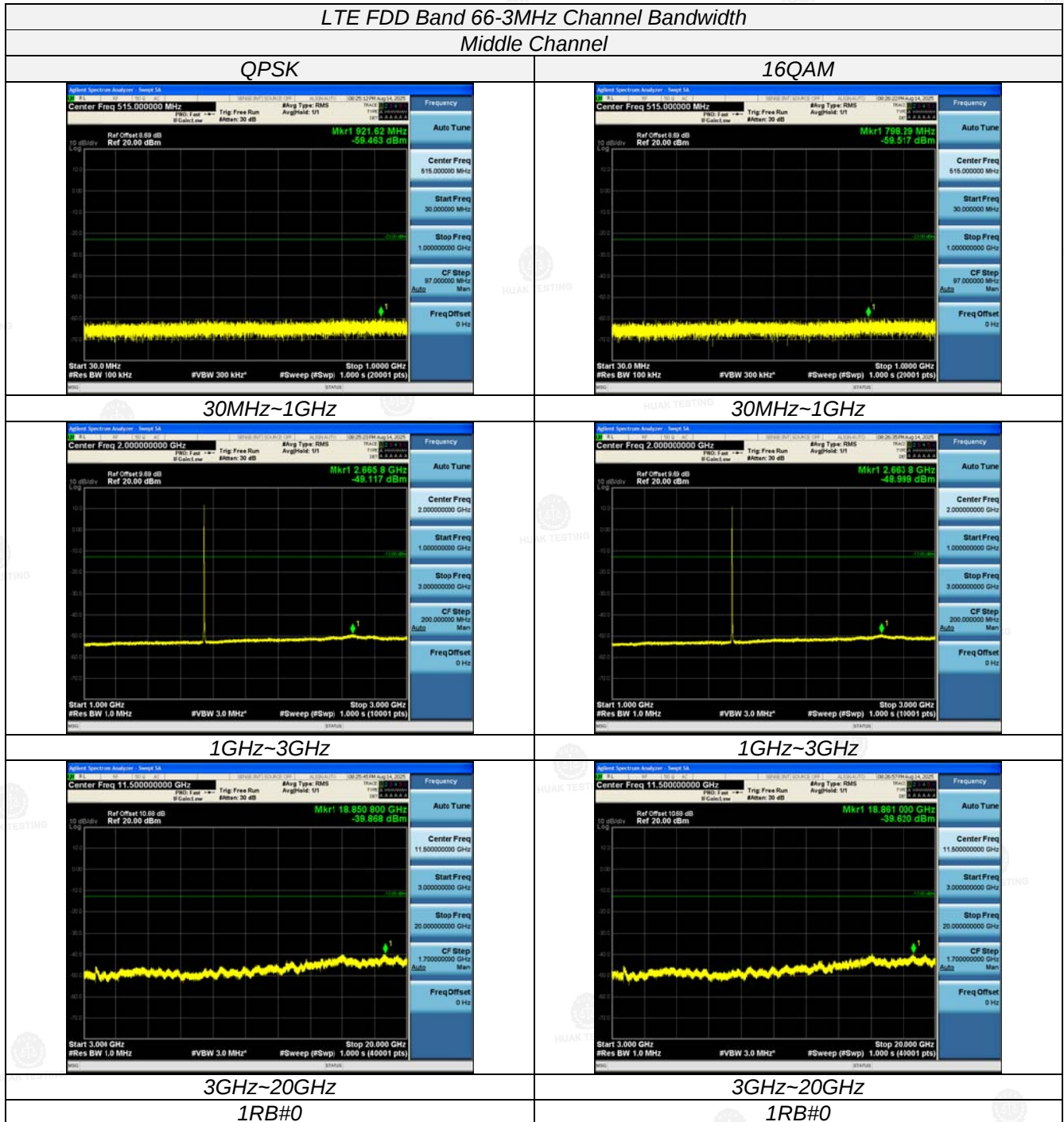
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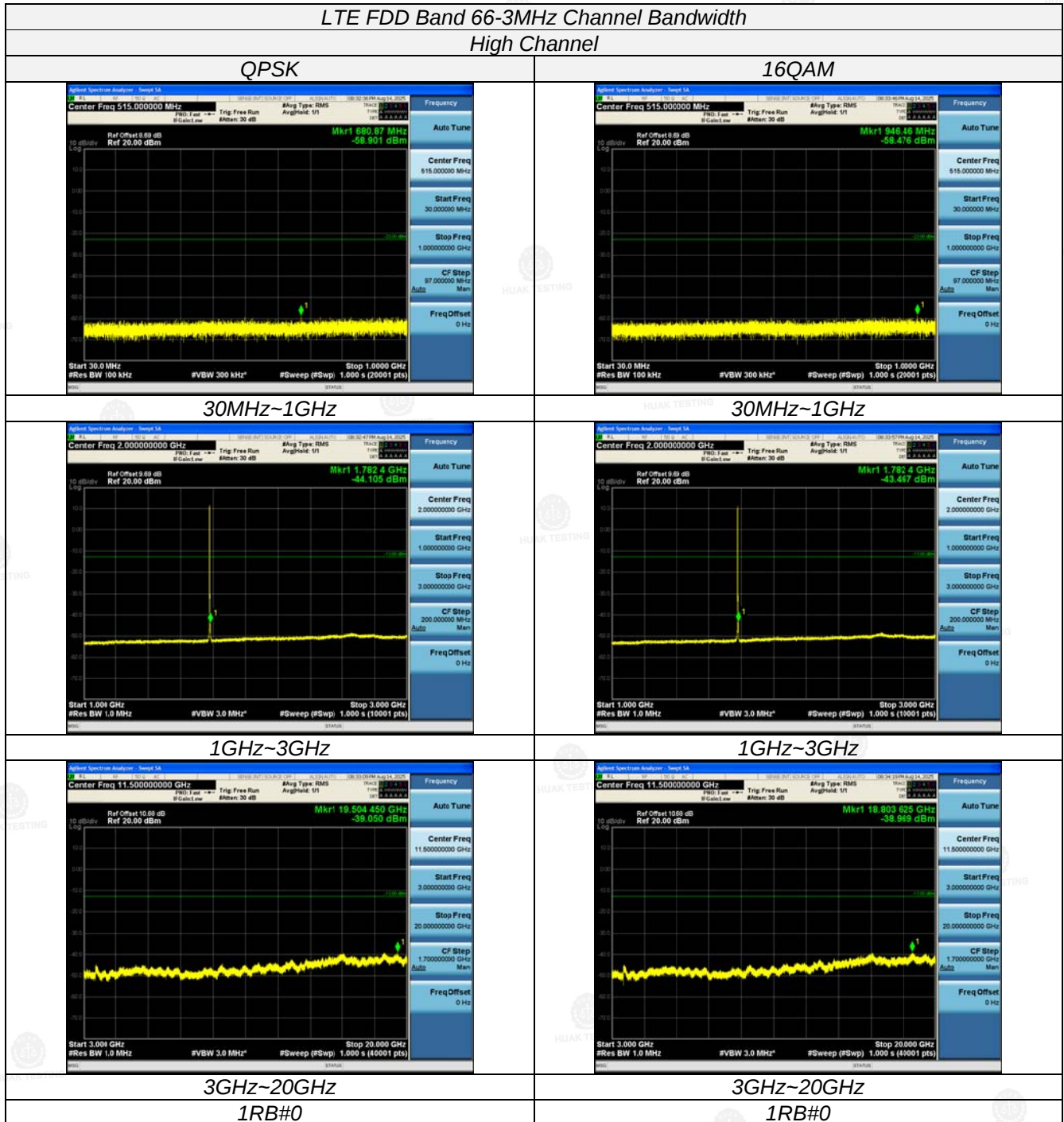
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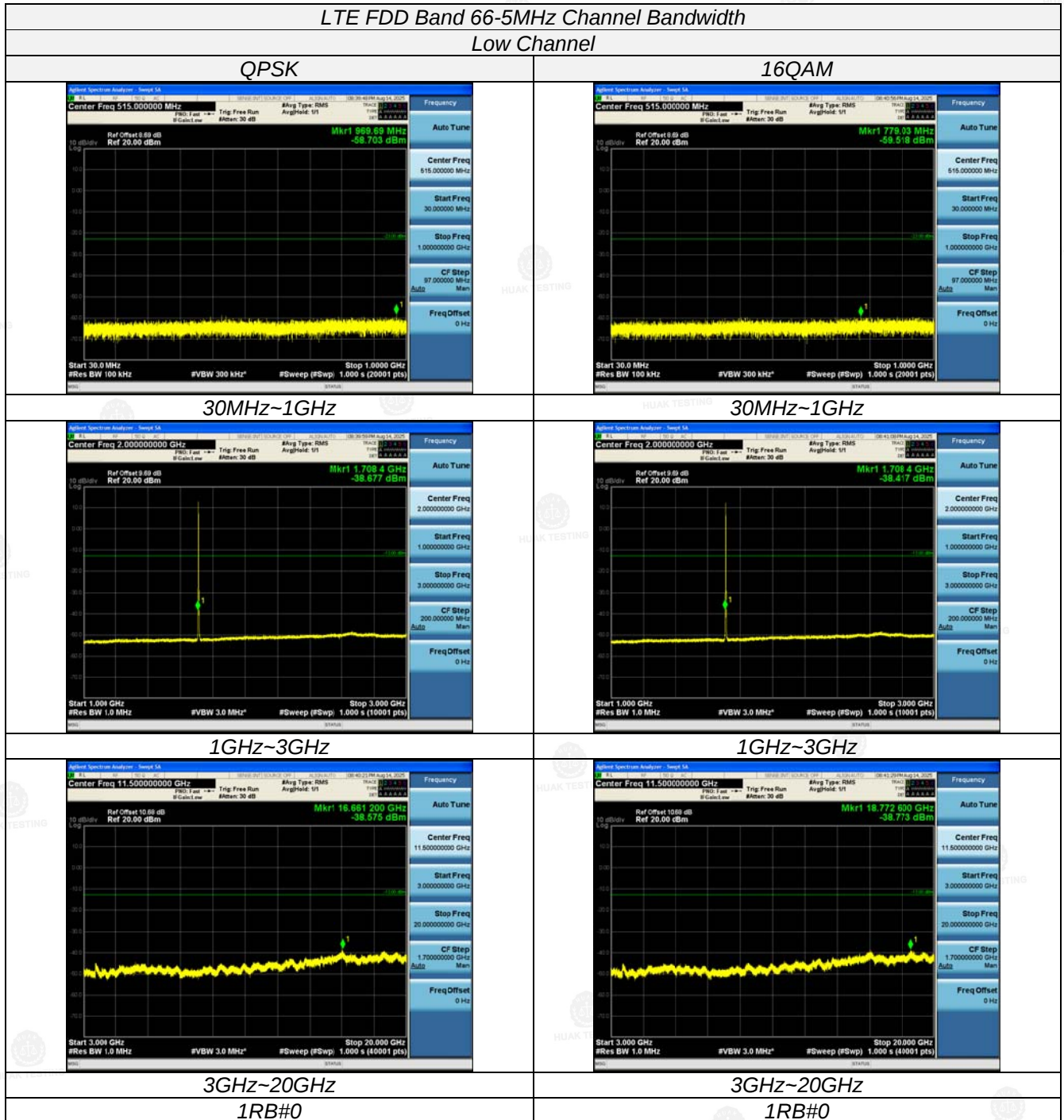
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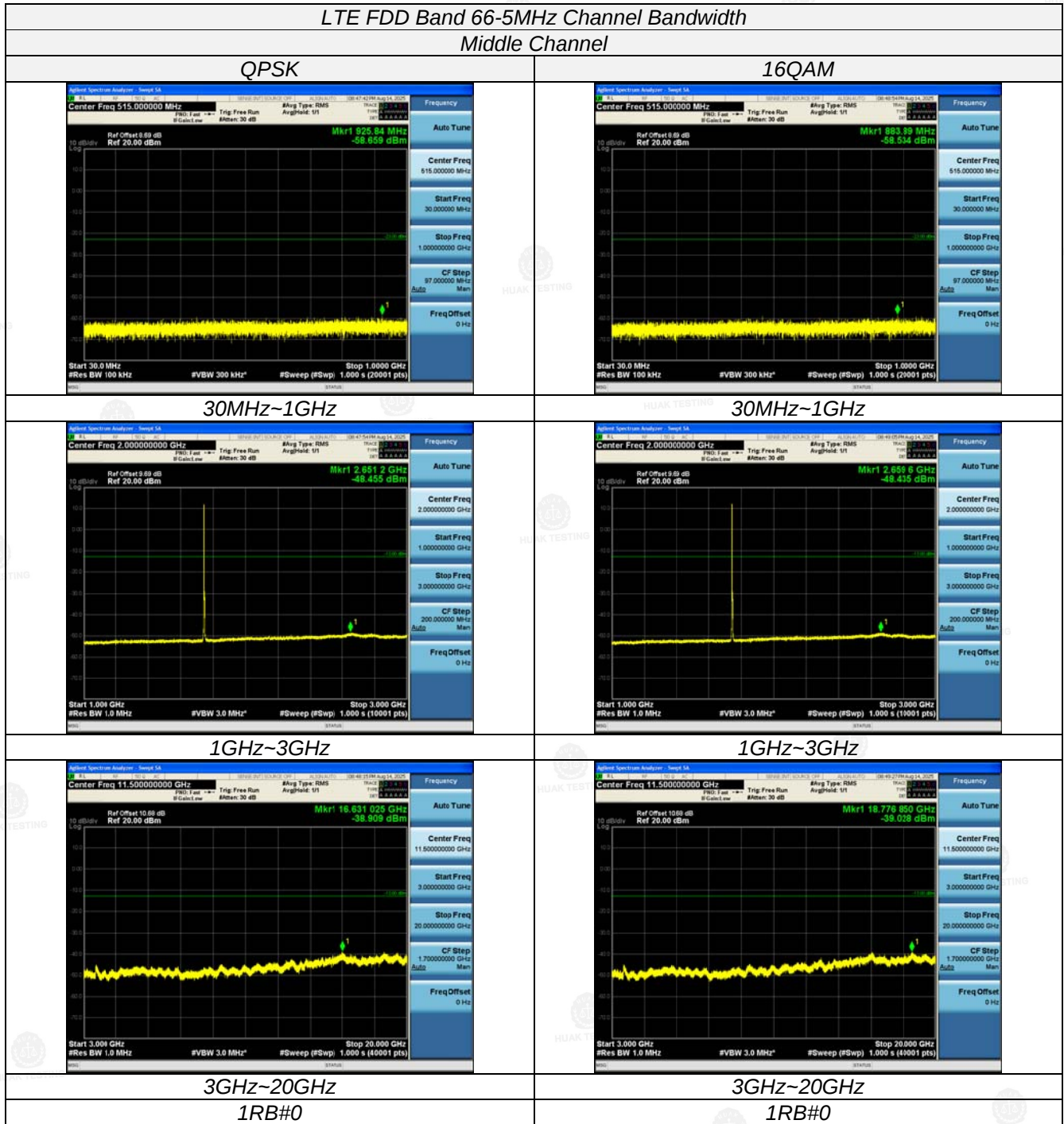
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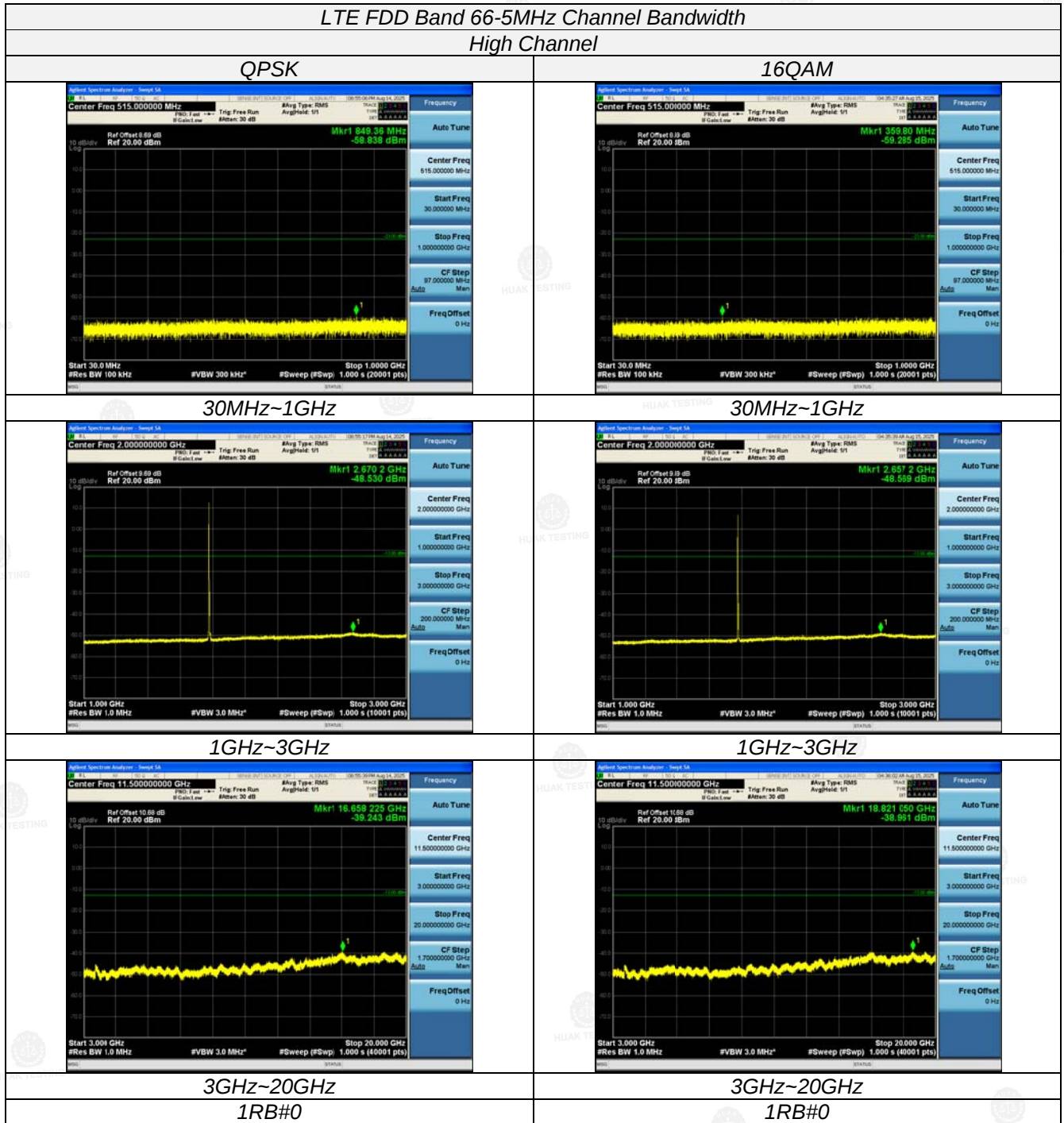


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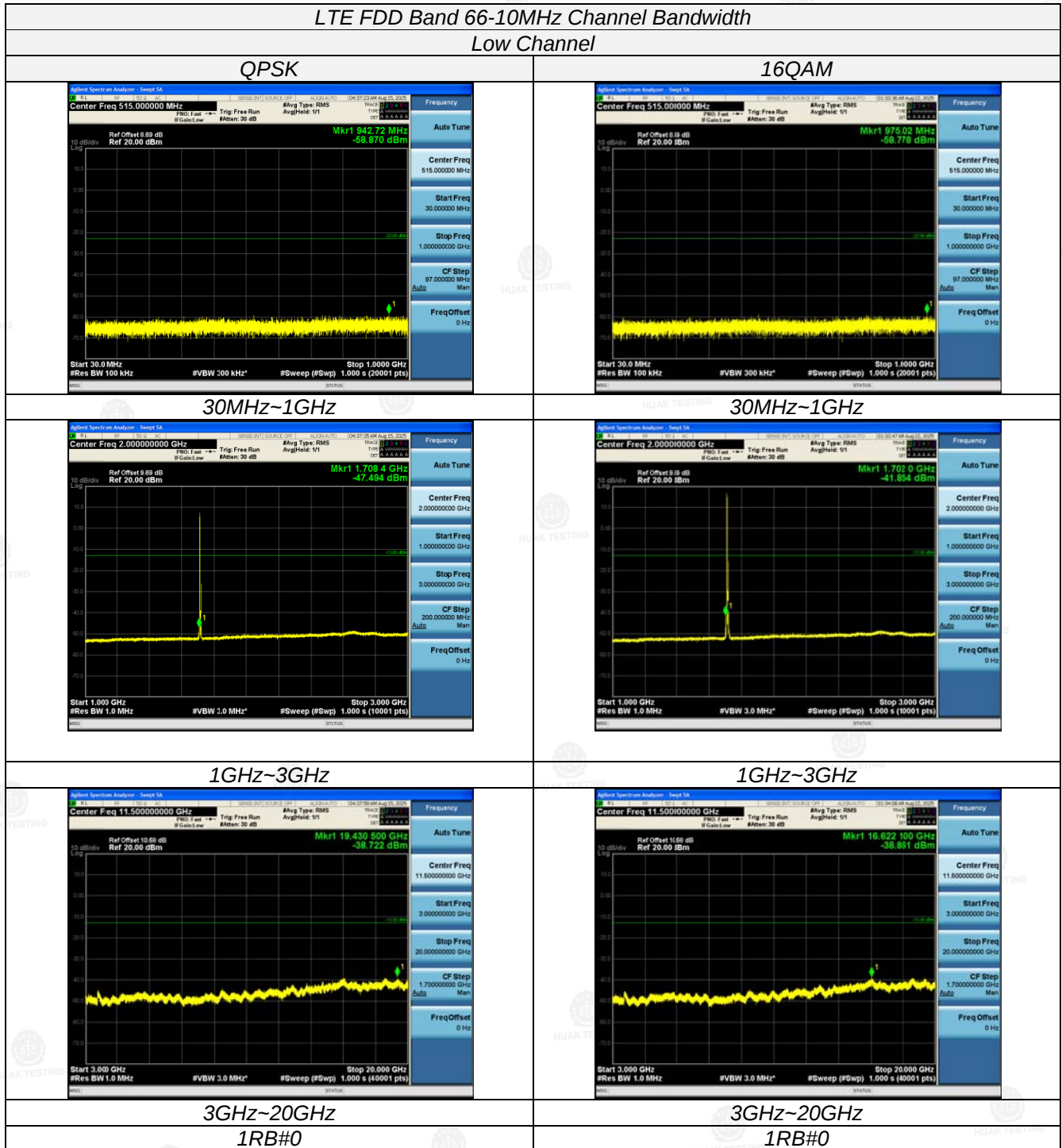


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Add.: 1-2/F., Building B2, Junfeng Zhongcheng Zhizao Innovation Park, Heping, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

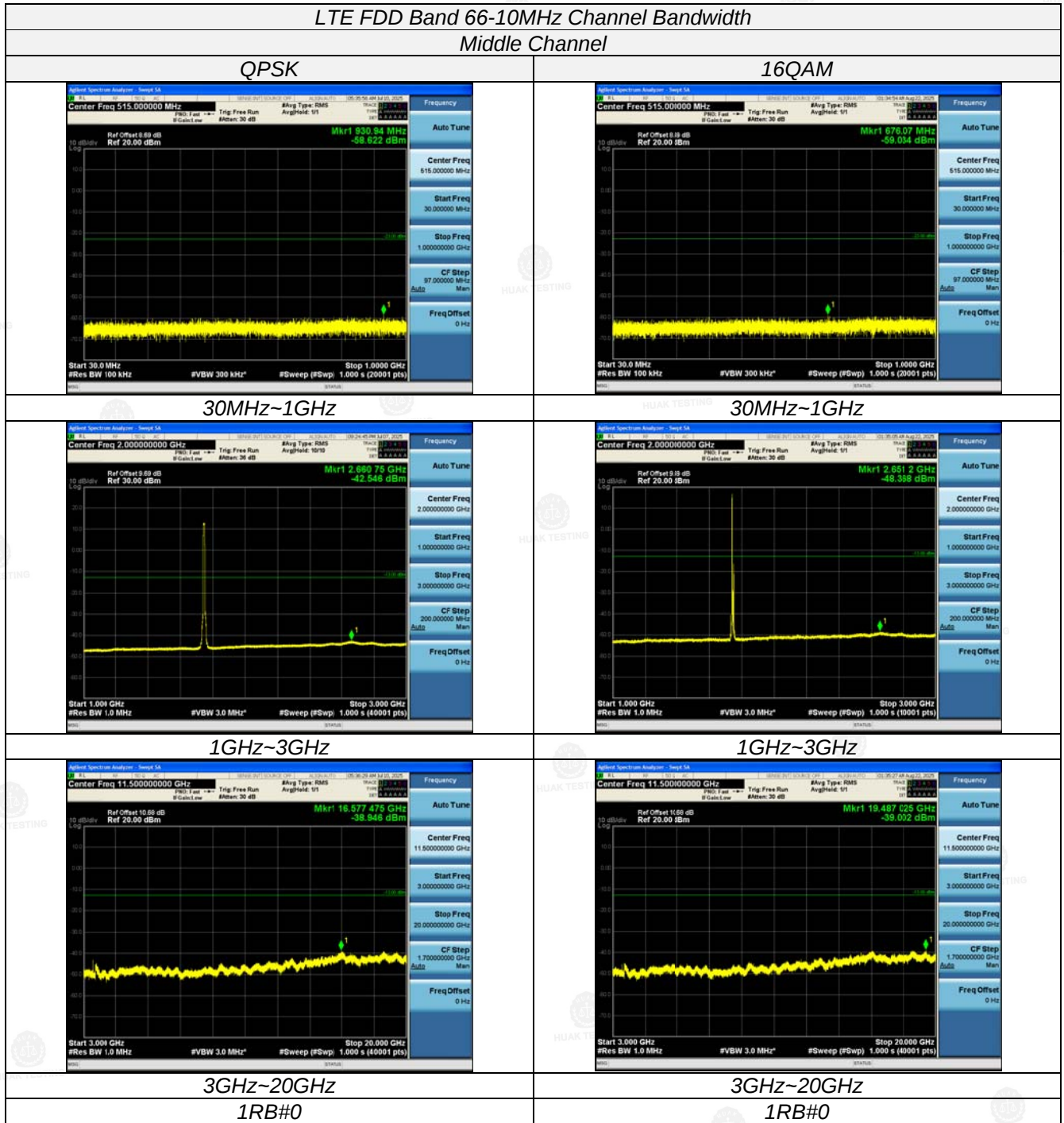


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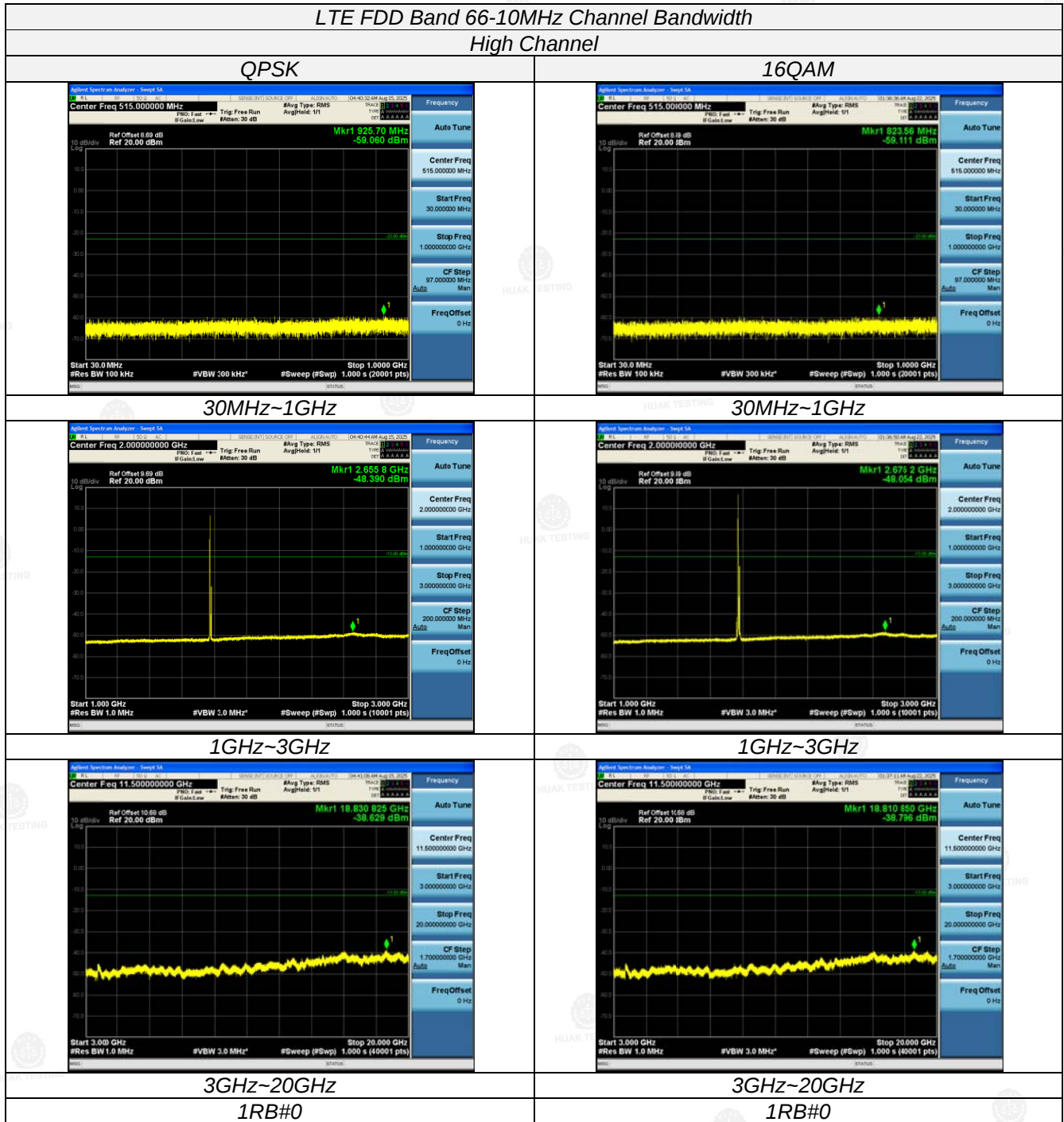


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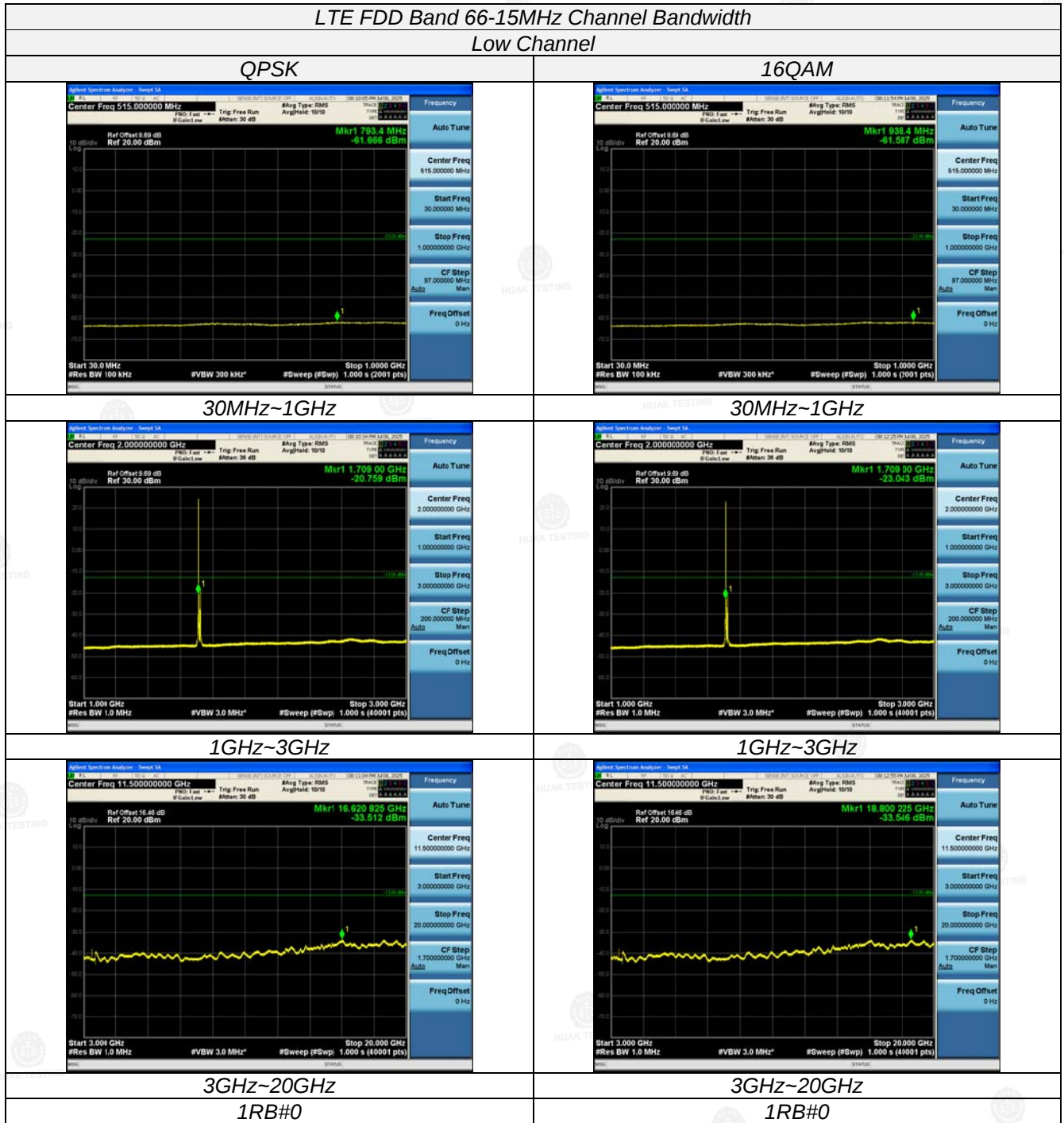
Shenzhen HUAKE Testing Technology Co., Ltd. Tel.: +86-0755-2302 9901 E-mail: info@huak.com Web.: www.huak.com
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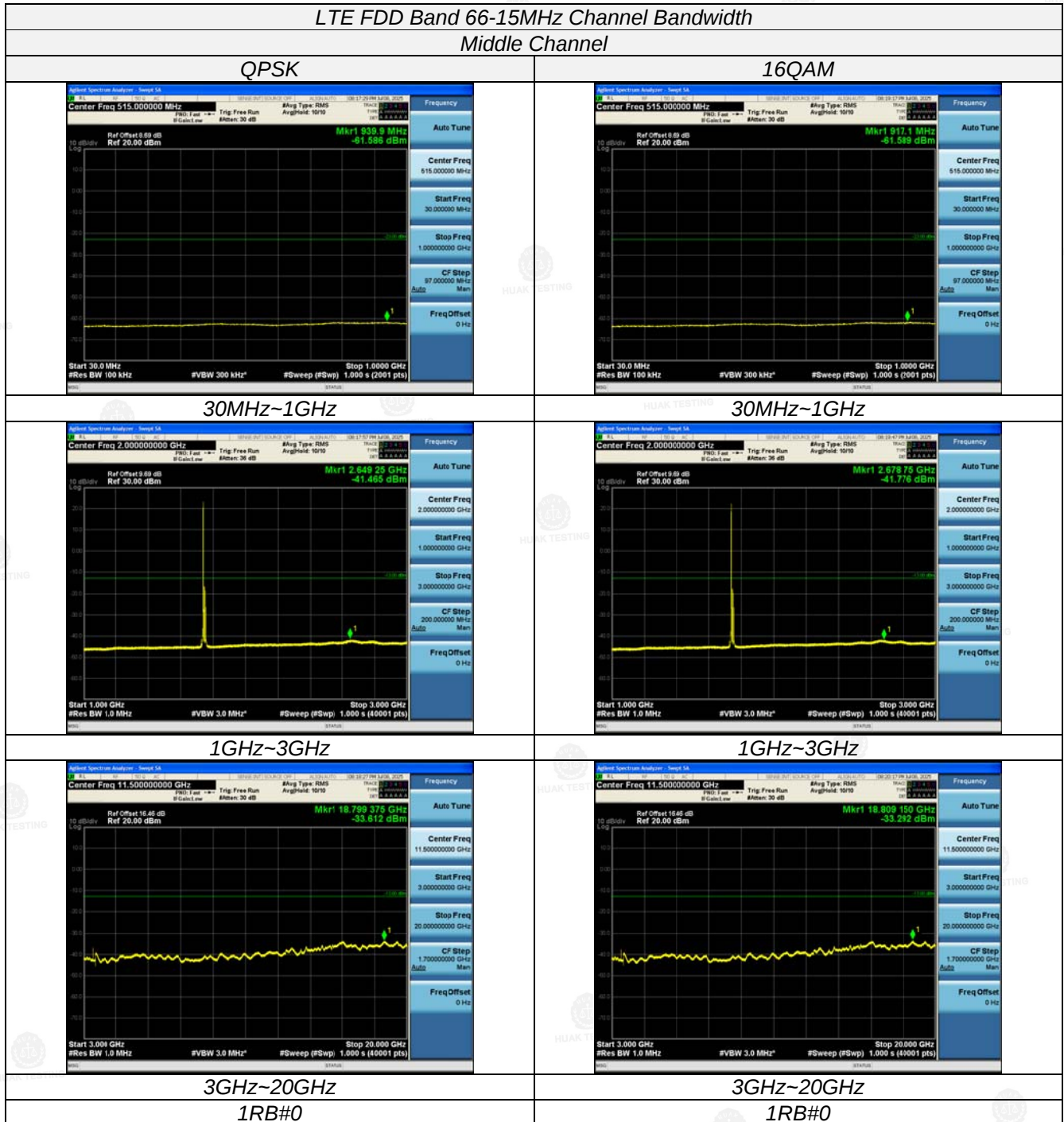
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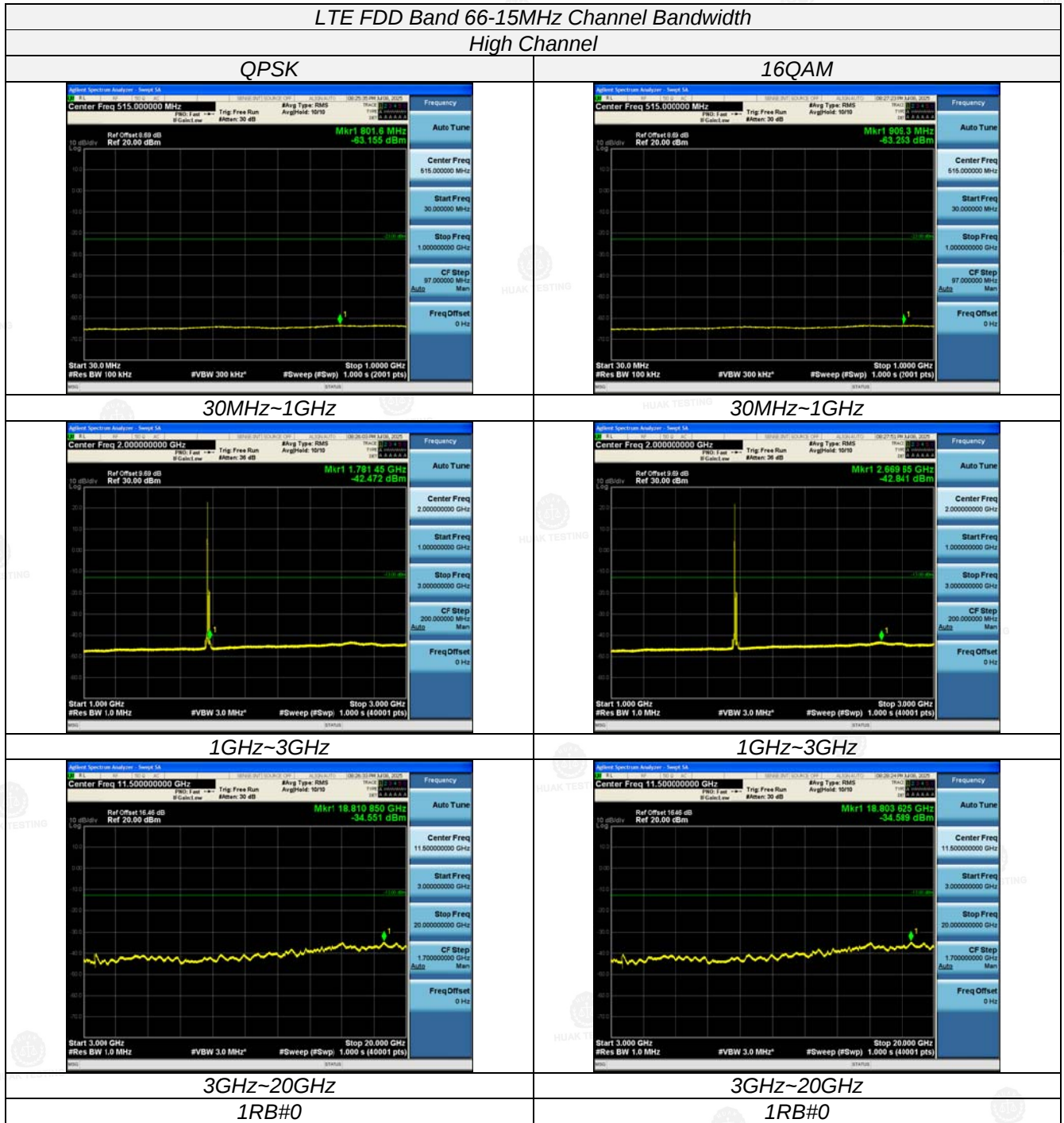
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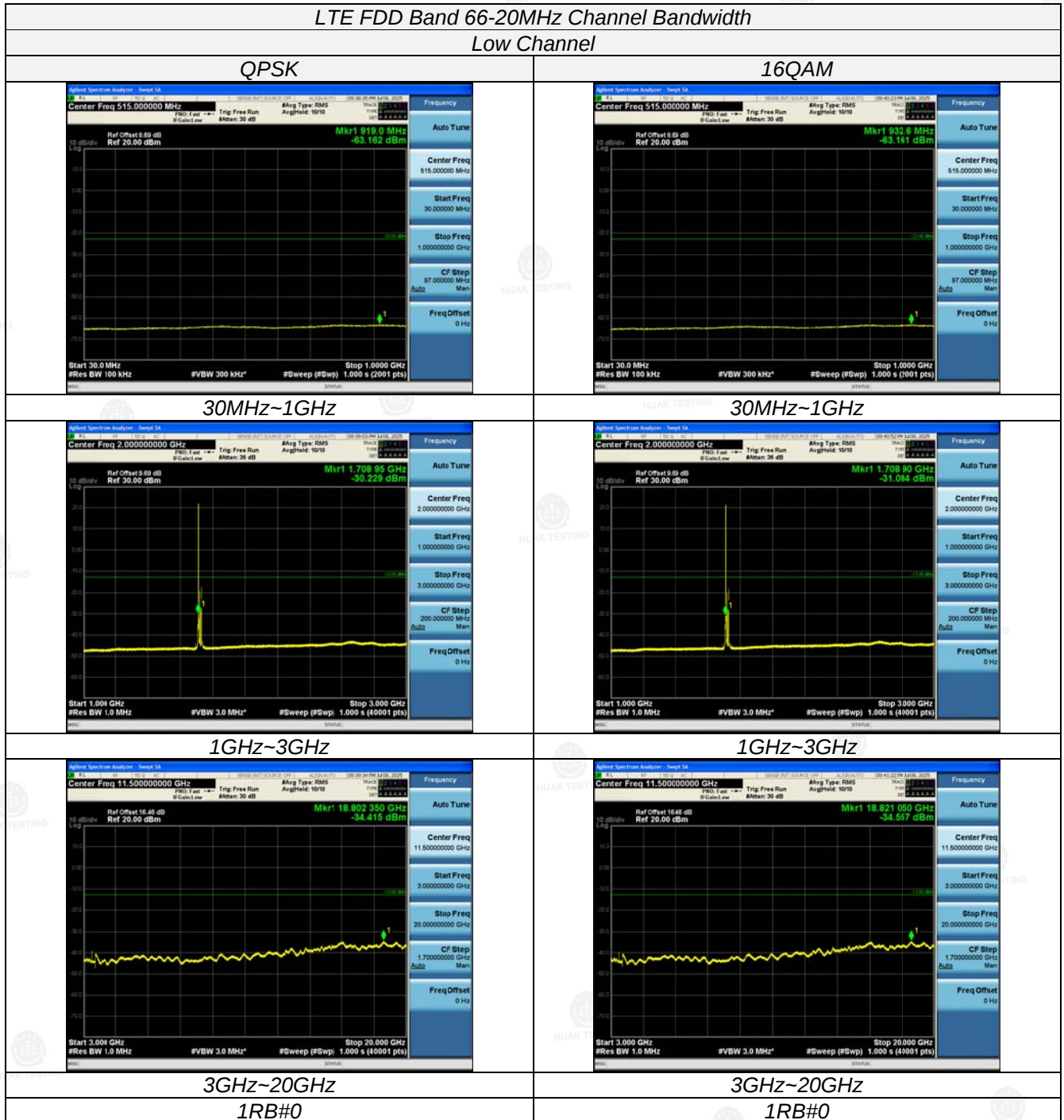
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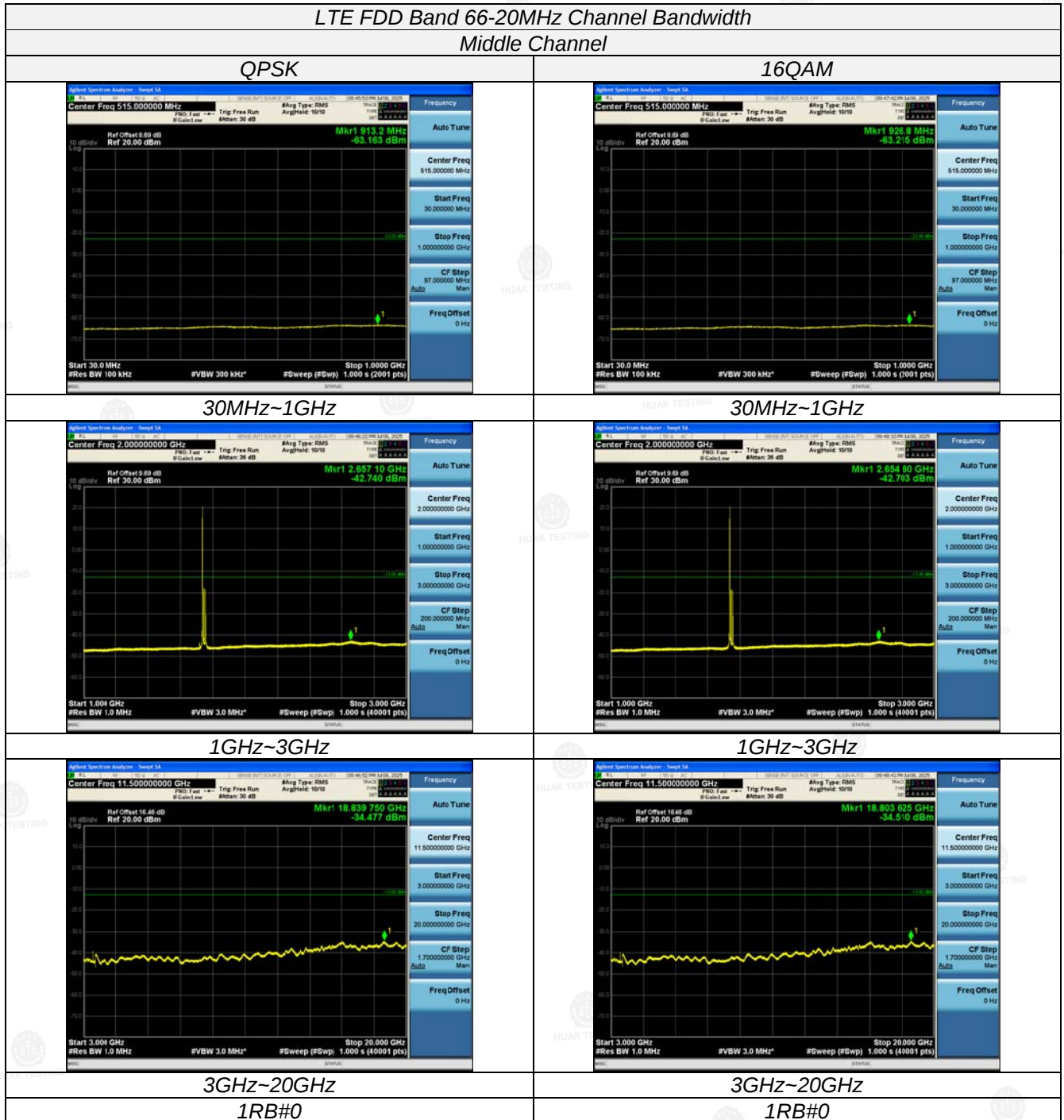
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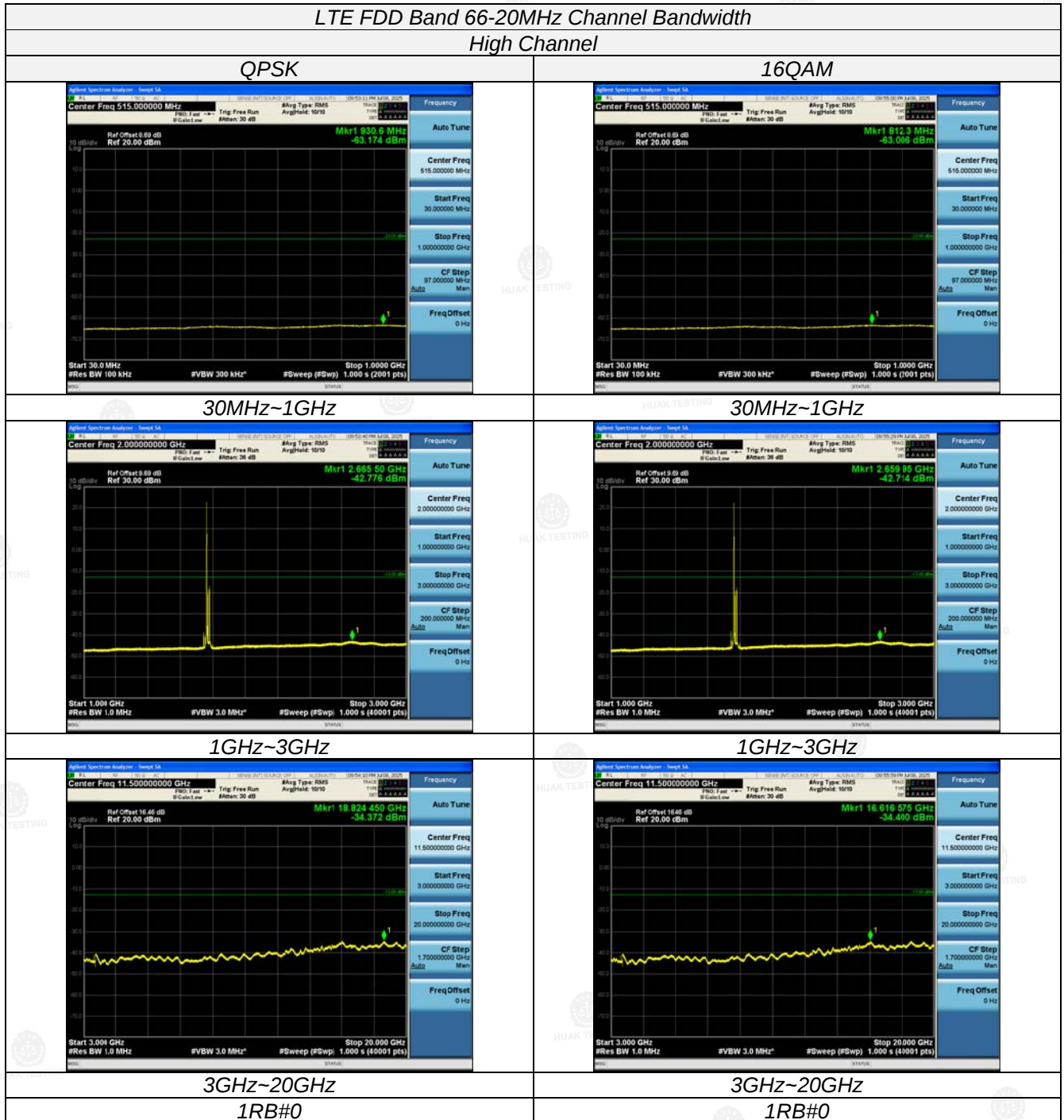
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Radiated Measurement:

Remark:

1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 66; recorded worst case for each Channel Bandwidth of LTE FDD Band 66.
2. $EIRP = P_{Mea}(dBm) - P_{cl}(dB) + G_a(dBi)$
3. We were not recorded other points as values lower than limits.
4. $Margin = Limit - EIRP$

LTE FDD Band 66 Channel Bandwidth 1.4MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3421.4	-46.95	4.02	3.00	12.50	-38.47	-13.00	25.47	H
5132.1	-47.36	5.11	3.00	13.38	-39.09	-13.00	26.09	H
3421.4	-49.72	4.02	3.00	12.50	-41.24	-13.00	28.24	V
5132.1	-49.40	5.11	3.00	13.38	-41.13	-13.00	28.13	V

LTE FDD Band 66 Channel Bandwidth 1.4MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.99	4.02	3.00	12.45	-39.56	-13.00	26.56	H
5235	-47.49	5.11	3.00	13.38	-39.22	-13.00	26.22	H
3490	-49.14	4.02	3.00	12.45	-40.71	-13.00	27.71	V
5235	-47.60	5.11	3.00	13.38	-39.33	-13.00	26.33	V

LTE FDD Band 66 Channel Bandwidth 1.4MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3558.6	-47.01	4.02	3.00	12.21	-38.82	-13.00	25.82	H
5337.9	-47.14	5.11	3.00	13.26	-38.99	-13.00	25.99	H
3558.6	-49.92	4.02	3.00	12.21	-41.73	-13.00	28.73	V
5337.9	-49.21	5.11	3.00	13.26	-41.06	-13.00	28.06	V

LTE FDD Band 66 Channel Bandwidth 3MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3423.0	-46.21	4.02	3.00	12.50	-37.73	-13.00	24.73	H
5134.5	-47.00	5.11	3.00	13.38	-38.73	-13.00	25.73	H
3423.0	-49.60	4.02	3.00	12.50	-41.12	-13.00	28.12	V
5134.5	-49.38	5.11	3.00	13.38	-41.11	-13.00	28.11	V

LTE FDD Band 66 Channel Bandwidth 3MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.15	4.02	3.00	12.45	-38.72	-13.00	25.72	H
5235	-47.58	5.11	3.00	13.38	-39.31	-13.00	26.31	H
3490	-49.05	4.02	3.00	12.45	-40.62	-13.00	27.62	V
5235	-47.74	5.11	3.00	13.38	-39.47	-13.00	26.47	V

LTE FDD Band 66 Channel Bandwidth 3MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3557	-46.25	4.02	3.00	12.21	-38.06	-13.00	25.06	H
5335.5	-46.99	5.11	3.00	13.26	-38.84	-13.00	25.84	H
3557	-49.62	4.02	3.00	12.21	-41.43	-13.00	28.43	V
5335.5	-50.12	5.11	3.00	13.26	-41.97	-13.00	28.97	V

LTE FDD Band 66 Channel Bandwidth 5MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3425.0	-46.47	4.02	3.00	12.50	-37.99	-13.00	24.99	H
5137.5	-47.02	5.11	3.00	13.38	-38.75	-13.00	25.75	H
3425.0	-49.82	4.02	3.00	12.50	-41.34	-13.00	28.34	V
5137.5	-49.48	5.11	3.00	13.38	-41.21	-13.00	28.21	V

LTE FDD Band 66 Channel Bandwidth 5MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.97	4.02	3.00	12.45	-39.54	-13.00	26.54	H
5235	-47.87	5.11	3.00	13.38	-39.60	-13.00	26.60	H
3490	-48.83	4.02	3.00	12.45	-40.40	-13.00	27.40	V
5235	-48.01	5.11	3.00	13.38	-39.74	-13.00	26.74	V

LTE FDD Band 66 Channel Bandwidth 5MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3555	-47.00	4.02	3.00	12.21	-38.81	-13.00	25.81	H
5332.5	-47.80	5.11	3.00	13.26	-39.65	-13.00	26.65	H
3555	-49.13	4.02	3.00	12.21	-40.94	-13.00	27.94	V
5332.5	-49.35	5.11	3.00	13.26	-41.20	-13.00	28.20	V

LTE FDD Band 66 Channel Bandwidth 10MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3430.0	-46.20	4.02	3.00	12.50	-37.72	-13.00	24.72	H
5145.0	-47.24	5.11	3.00	13.38	-38.97	-13.00	25.97	H
3430.0	-49.36	4.02	3.00	12.50	-40.88	-13.00	27.88	V
5145.0	-49.67	5.11	3.00	13.38	-41.40	-13.00	28.40	V

LTE FDD Band 66 Channel Bandwidth 10MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.89	4.02	3.00	12.45	-39.46	-13.00	26.46	H
5235	-47.87	5.11	3.00	13.38	-39.60	-13.00	26.60	H
3490	-48.64	4.02	3.00	12.45	-40.21	-13.00	27.21	V
5235	-48.10	5.11	3.00	13.38	-39.83	-13.00	26.83	V

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LTE FDD Band 66 Channel Bandwidth 10MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3550	-46.68	4.02	3.00	12.21	-38.49	-13.00	25.49	H
5325	-47.82	5.11	3.00	13.26	-39.67	-13.00	26.67	H
3550	-49.31	4.02	3.00	12.21	-41.12	-13.00	28.12	V
5325	-49.44	5.11	3.00	13.26	-41.29	-13.00	28.29	V

LTE FDD Band 66 Channel Bandwidth 15MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3435.0	-46.27	4.02	3.00	12.50	-37.79	-13.00	24.79	H
5152.5	-47.04	5.11	3.00	13.38	-38.77	-13.00	25.77	H
3435.0	-49.99	4.02	3.00	12.50	-41.51	-13.00	28.51	V
5152.5	-49.14	5.11	3.00	13.38	-40.87	-13.00	27.87	V

LTE FDD Band 66 Channel Bandwidth 15MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.44	4.02	3.00	12.45	-39.01	-13.00	26.01	H
5235	-47.85	5.11	3.00	13.38	-39.58	-13.00	26.58	H
3490	-49.41	4.02	3.00	12.45	-40.98	-13.00	27.98	V
5235	-47.39	5.11	3.00	13.38	-39.12	-13.00	26.12	V

LTE FDD Band 66 Channel Bandwidth 15MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3545	-46.28	4.02	3.00	12.21	-38.09	-13.00	25.09	H
5317.5	-47.52	5.11	3.00	13.26	-39.37	-13.00	26.37	H
3545	-49.77	4.02	3.00	12.21	-41.58	-13.00	28.58	V
5317.5	-49.66	5.11	3.00	13.26	-41.51	-13.00	28.51	V

LTE FDD Band 66 Channel Bandwidth 20MHz QPSK Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3440.0	-47.06	4.02	3.00	12.50	-38.58	-13.00	25.58	H
5160.0	-47.14	5.11	3.00	13.38	-38.87	-13.00	25.87	H
3440.0	-50.01	4.02	3.00	12.50	-41.53	-13.00	28.53	V
5160.0	-49.51	5.11	3.00	13.38	-41.24	-13.00	28.24	V

LTE FDD Band 66 Channel Bandwidth 20MHz QPSK Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.17	4.02	3.00	12.45	-38.74	-13.00	25.74	H
5235	-47.54	5.11	3.00	13.38	-39.27	-13.00	26.27	H
3490	-48.59	4.02	3.00	12.45	-40.16	-13.00	27.16	V
5235	-48.02	5.11	3.00	13.38	-39.75	-13.00	26.75	V

LTE FDD Band 66 Channel Bandwidth 20MHz QPSK High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3540	-46.23	4.02	3.00	12.21	-38.04	-13.00	25.04	H
5310	-47.59	5.11	3.00	13.26	-39.44	-13.00	26.44	H
3540	-49.62	4.02	3.00	12.21	-41.43	-13.00	28.43	V
5310	-49.29	5.11	3.00	13.26	-41.14	-13.00	28.14	V

LTE FDD Band 66 Channel Bandwidth 1.4MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3421.4	-46.52	4.02	3.00	12.50	-38.04	-13.00	25.04	H
5132.1	-47.37	5.11	3.00	13.38	-39.10	-13.00	26.10	H
3421.4	-49.22	4.02	3.00	12.50	-40.74	-13.00	27.74	V
5132.1	-49.42	5.11	3.00	13.38	-41.15	-13.00	28.15	V

LTE FDD Band 66 Channel Bandwidth 1.4MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.14	4.02	3.00	12.45	-38.71	-13.00	25.71	H
5235	-47.77	5.11	3.00	13.38	-39.50	-13.00	26.50	H
3490	-49.24	4.02	3.00	12.45	-40.81	-13.00	27.81	V
5235	-47.35	5.11	3.00	13.38	-39.08	-13.00	26.08	V

LTE FDD Band 66 Channel Bandwidth 1.4MHz 16QAM High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3558.6	-46.36	4.02	3.00	12.21	-38.17	-13.00	25.17	H
5337.9	-47.20	5.11	3.00	13.26	-39.05	-13.00	26.05	H
3558.6	-49.47	4.02	3.00	12.21	-41.28	-13.00	28.28	V
5337.9	-49.58	5.11	3.00	13.26	-41.43	-13.00	28.43	V

LTE FDD Band 66 Channel Bandwidth 3MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3423.0	-46.43	4.02	3.00	12.50	-37.95	-13.00	24.95	H
5134.5	-46.78	5.11	3.00	13.38	-38.51	-13.00	25.51	H
3423.0	-50.04	4.02	3.00	12.50	-41.56	-13.00	28.56	V
5134.5	-48.96	5.11	3.00	13.38	-40.69	-13.00	27.69	V

LTE FDD Band 66 Channel Bandwidth 3MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.73	4.02	3.00	12.45	-39.30	-13.00	26.30	H
5235	-47.37	5.11	3.00	13.38	-39.10	-13.00	26.10	H
3490	-49.32	4.02	3.00	12.45	-40.89	-13.00	27.89	V
5235	-48.03	5.11	3.00	13.38	-39.76	-13.00	26.76	V

LTE FDD Band 66 Channel Bandwidth 3MHz 16QAM High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3557	-47.00	4.02	3.00	12.21	-38.81	-13.00	25.81	H
5335.5	-47.93	5.11	3.00	13.26	-39.78	-13.00	26.78	H
3557	-50.08	4.02	3.00	12.21	-41.89	-13.00	28.89	V
5335.5	-49.85	5.11	3.00	13.26	-41.70	-13.00	28.70	V

LTE FDD Band 66 Channel Bandwidth 5MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3425.0	-47.11	4.02	3.00	12.50	-38.63	-13.00	25.63	H
5137.5	-47.09	5.11	3.00	13.38	-38.82	-13.00	25.82	H
3425.0	-50.01	4.02	3.00	12.50	-41.53	-13.00	28.53	V
5137.5	-49.28	5.11	3.00	13.38	-41.01	-13.00	28.01	V

LTE FDD Band 66 Channel Bandwidth 5MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.74	4.02	3.00	12.45	-39.31	-13.00	26.31	H
5235	-48.31	5.11	3.00	13.38	-40.04	-13.00	27.04	H
3490	-49.10	4.02	3.00	12.45	-40.67	-13.00	27.67	V
5235	-48.09	5.11	3.00	13.38	-39.82	-13.00	26.82	V

LTE FDD Band 66 Channel Bandwidth 5MHz 16QAM High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3555	-46.45	4.02	3.00	12.21	-38.26	-13.00	25.26	H
5332.5	-47.59	5.11	3.00	13.26	-39.44	-13.00	26.44	H
3555	-49.45	4.02	3.00	12.21	-41.26	-13.00	28.26	V
5332.5	-50.16	5.11	3.00	13.26	-42.01	-13.00	29.01	V

LTE FDD Band 66 Channel Bandwidth 10MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3430.0	-46.70	4.02	3.00	12.50	-38.22	-13.00	25.22	H
5145.0	-47.04	5.11	3.00	13.38	-38.77	-13.00	25.77	H
3430.0	-49.99	4.02	3.00	12.50	-41.51	-13.00	28.51	V
5145.0	-49.20	5.11	3.00	13.38	-40.93	-13.00	27.93	V

LTE FDD Band 66 Channel Bandwidth 10MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.58	4.02	3.00	12.45	-39.15	-13.00	26.15	H
5235	-48.03	5.11	3.00	13.38	-39.76	-13.00	26.76	H
3490	-48.67	4.02	3.00	12.45	-40.24	-13.00	27.24	V
5235	-47.57	5.11	3.00	13.38	-39.30	-13.00	26.30	V

LTE FDD Band 66 Channel Bandwidth 10MHz 16QAM High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3550	-46.81	4.02	3.00	12.21	-38.62	-13.00	25.62	H
5325	-47.80	5.11	3.00	13.26	-39.65	-13.00	26.65	H
3550	-49.34	4.02	3.00	12.21	-41.15	-13.00	28.15	V
5325	-49.73	5.11	3.00	13.26	-41.58	-13.00	28.58	V

LTE FDD Band 66 Channel Bandwidth 15MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3435.0	-46.91	4.02	3.00	12.50	-38.43	-13.00	25.43	H
5152.5	-47.27	5.11	3.00	13.38	-39.00	-13.00	26.00	H
3435.0	-49.63	4.02	3.00	12.50	-41.15	-13.00	28.15	V
5152.5	-48.82	5.11	3.00	13.38	-40.55	-13.00	27.55	V

LTE FDD Band 66 Channel Bandwidth 15MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.88	4.02	3.00	12.45	-39.45	-13.00	26.45	H
5235	-47.77	5.11	3.00	13.38	-39.50	-13.00	26.50	H
3490	-49.07	4.02	3.00	12.45	-40.64	-13.00	27.64	V
5235	-48.06	5.11	3.00	13.38	-39.79	-13.00	26.79	V

LTE FDD Band 66 Channel Bandwidth 15MHz 16QAM High Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3545	-46.67	4.02	3.00	12.21	-38.48	-13.00	25.48	H
5317.5	-47.86	5.11	3.00	13.26	-39.71	-13.00	26.71	H
3545	-50.07	4.02	3.00	12.21	-41.88	-13.00	28.88	V
5317.5	-49.69	5.11	3.00	13.26	-41.54	-13.00	28.54	V

LTE FDD Band 66 Channel Bandwidth 20MHz 16QAM Low Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	Peak EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3440.0	-47.04	4.02	3.00	12.50	-38.56	-13.00	25.56	H
5160.0	-46.71	5.11	3.00	13.38	-38.44	-13.00	25.44	H
3440.0	-49.37	4.02	3.00	12.50	-40.89	-13.00	27.89	V
5160.0	-49.07	5.11	3.00	13.38	-40.80	-13.00	27.80	V

LTE FDD Band 66 Channel Bandwidth 20MHz 16QAM Middle Channel

Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3490	-47.60	4.02	3.00	12.45	-39.17	-13.00	26.17	H
5235	-47.38	5.11	3.00	13.38	-39.11	-13.00	26.11	H
3490	-49.29	4.02	3.00	12.45	-40.86	-13.00	27.86	V
5235	-47.34	5.11	3.00	13.38	-39.07	-13.00	26.07	V

The results shown in this test report refer only to the sample(s) tested unless otherwise stated and the sample(s) are retained for 15 days only. The document is issued by Shenzhen HUAKE Testing Technology Co., Ltd., this document cannot be reproduced except in full with our prior written permission.

LTE FDD Band 66 Channel Bandwidth 20MHz 16QAM High Channel

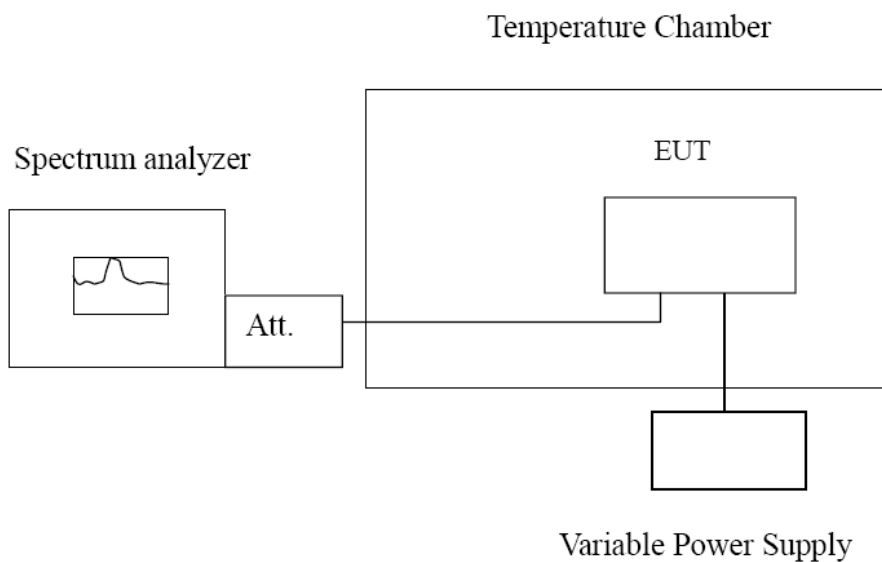
Frequency (MHz)	PMea (dBm)	Pcl (dB)	Diatance	Ga Antenna Gain(dB)	EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
3540	-46.89	4.02	3.00	12.21	-38.70	-13.00	25.70	H
5310	-47.52	5.11	3.00	13.26	-39.37	-13.00	26.37	H
3540	-49.09	4.02	3.00	12.21	-40.90	-13.00	27.90	V
5310	-49.57	5.11	3.00	13.26	-41.42	-13.00	28.42	V

3.6 Frequency Stability under Temperature & Voltage Variations

LIMIT

According to §27.54, §2.1055 requirement, the frequency stability shall be sufficient to ensure that the fundamental emissions stay within the authorized bands of operation and should not exceed 2.5ppm.

TEST CONFIGURATION



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D.

Frequency Stability Under Temperature Variations:

In order to measure the carrier frequency under the condition of AFC lock, it is necessary to make measurements with the EUT in a "call mode". This is accomplished with the use of R&S CMW500 DIGITAL RADIO COMMUNICATION TESTER.

1. Measure the carrier frequency at room temperature.
2. Subject the EUT to overnight soak at -30°C.
3. With the EUT, powered via nominal voltage, connected to the CMW500 and in a simulated call on middle channel for LTE band 4, measure the carrier frequency. These measurements should be made within 2 minutes of Powering up the EUT, to prevent significant self-warming.
4. Repeat the above measurements at 10°C increments from -30°C to +50°C. Allow at least 1.5 hours at each temperature, unpowered, before making measurements.
5. Re-measure carrier frequency at room temperature with nominal voltage. Vary supply voltage from minimum voltage to maximum voltage, in 0.1Volt increments re-measuring carrier frequency at each voltage. Pause at nominal voltage for 1.5 hours unpowered, to allow any self-heating to stabilize, before continuing.
6. Subject the EUT to overnight soak at +50°C.
7. With the EUT, powered via nominal voltage, connected to the CMW500 and in a simulated call on the centre channel, measure the carrier frequency. These measurements should be made within 2 minutes of Powering up the EUT, to prevent significant self-warming.
8. Repeat the above measurements at 10 °C increments from +50°C to -30°C. Allow at least 1.5 hours at each temperature, unpowered, before making measurements.
9. At all temperature levels hold the temperature to +/- 0.5°C during the measurement procedure.

Frequency Stability Under Voltage Variations:

Set chamber temperature to 20℃. Use a variable AC power supply / DC power source to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency.

Reduce the input voltage to specify extreme voltage variation ($\pm 15\%$) and endpoint, record the maximum frequency change.

TEST RESULTS

Remark:

1. We tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE FDD Band 66; recorded worst case.

LTE Band 66, 1.4MHz bandwidth , QPSK (worst case of all bandwidths)

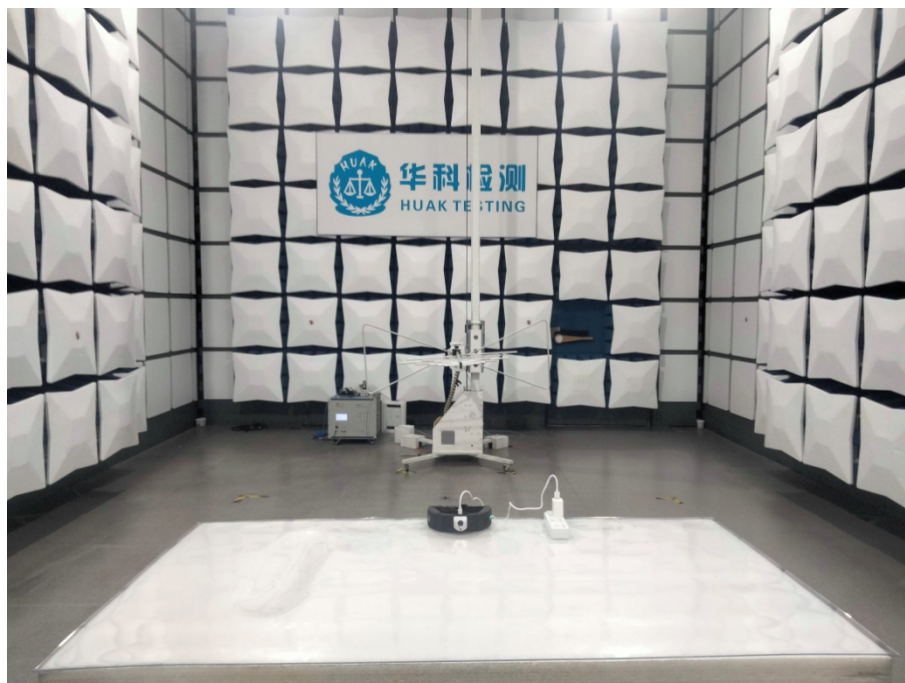
LTE FDD Band 66				
DC Power	Temperature (℃)	Frequency error(Hz)	Frequency error(ppm)	Verdict
4.25	20	5.61	0.003215	PASS
5.0	20	8.11	0.004648	PASS
5.75	20	-9.40	-0.005387	PASS
5.0	-30	3.09	0.001806	PASS
5.0	-20	3.35	0.001958	PASS
5.0	-10	5.09	0.002975	PASS
5.0	0	3.89	0.002274	PASS
5.0	10	-2.86	-0.001672	PASS
5.0	20	5.71	0.003338	PASS
5.0	30	-3.96	-0.002315	PASS
5.0	40	8.31	0.004858	PASS
5.0	50	-3.69	-0.002157	PASS

LTE Band 66, 1.4MHz bandwidth , 16QAM (worst case of all bandwidths)

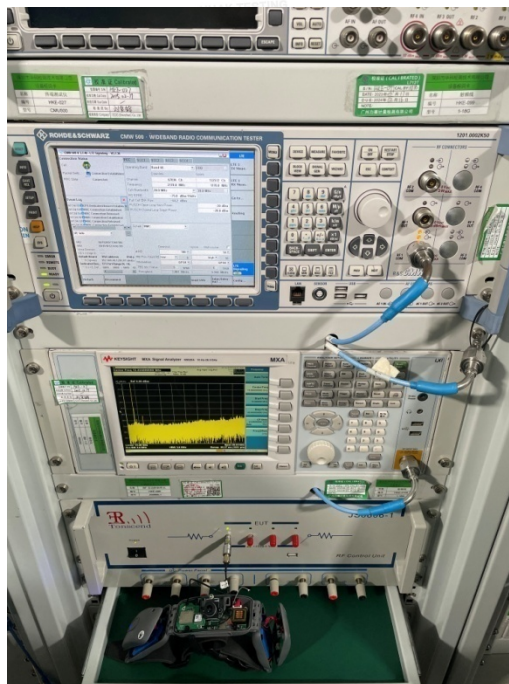
LTE FDD Band 66				
DC Power	Temperature (℃)	Frequency error(Hz)	Frequency error(ppm)	Verdict
4.25	20	9.01	0.005163	PASS
5.0	20	4.16	0.002384	PASS
5.75	20	3.13	0.001794	PASS
5.0	-30	-6.59	-0.003852	PASS
5.0	-20	-7.58	-0.004431	PASS
5.0	-10	4.46	0.002607	PASS
5.0	0	-5.81	-0.003396	PASS
5.0	10	1.87	0.001093	PASS
5.0	20	3.28	0.001917	PASS
5.0	30	-6.14	-0.003589	PASS
5.0	40	3.16	0.001847	PASS
5.0	50	4.52	0.002642	PASS

4 Test Setup Photos of the EUT

Radiated Emissions



RF Conducted Emission



5 Photos of the EUT

Reference to the report: ANNEX A of external photos and ANNEX B of internal photos.

.....**End of Report**.....